

Notice of References Cited	Application/Control No. 10/665,335	Applicant(s)/Patent Under Reexamination PAN ET AL.	
	Examiner Evan Pert	Art Unit 2826	Page 1 of 1

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	C	US-6,705,910	03-2004	Sheu et al.	445/24
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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